WHAT IS CLAIMED IS:

- 1. A semiconductor integrated circuit comprising:
- a ROM for storing confidential data thereon;
- a tester for testing the ROM; and

means for storing redundancy check data that has been obtained by performing a predetermined calculation on the confidential data,

wherein the tester includes a checker for performing the same type of calculation as the predetermined calculation on the confidential data that has been read out from the ROM, and

wherein a result of the calculation performed by the checker is compared to the redundancy check data stored on the storage means.

- The integrated circuit of Claim 1, wherein the storage means is included in the ROM.
- 3. The integrated circuit of Claim 2, wherein the redundancy check data and the confidential data are stored at mutually different addresses on the ROM.
- 4. The integrated circuit of Claim 2, wherein the redundancy check data and the confidential data are stored at the same address on the ROM.

- 5. A method of testing a semiconductor integrated circuit including a ROM that stores confidential data thereon, the method comprising the steps of:
- a) storing redundancy check data, which has been obtained by performing a predetermined calculation on the confidential data, on redundancy check data storage means of the integrated circuit;
- b) reading out the confidential data from the ROM and performing the same type of calculation as the predetermined calculation on the confidential data read out; and
- c) reading out the redundancy check data from the storage means and then comparing a result of the calculation performed in the step b) to the redundancy check data read out.